

Materials List for:

Data Acquisition Protocol for Determining Embedded Sensitivity Functions

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Materials

Name	Company	Catalog Number	Comments
Accelerometer	PCB	356B11	three used in testing
Impact hammer	PCB	086C01	
Data acquisition card	NI	9234	
DAQ chassis	NI	cDAQ-9171	or similar
Software	MATLAB		
Super glue	Loctite	454	
Handheld Shaker	PCB	394C06	for calibration